

Interaction with CMOS and Terminal Characteristics

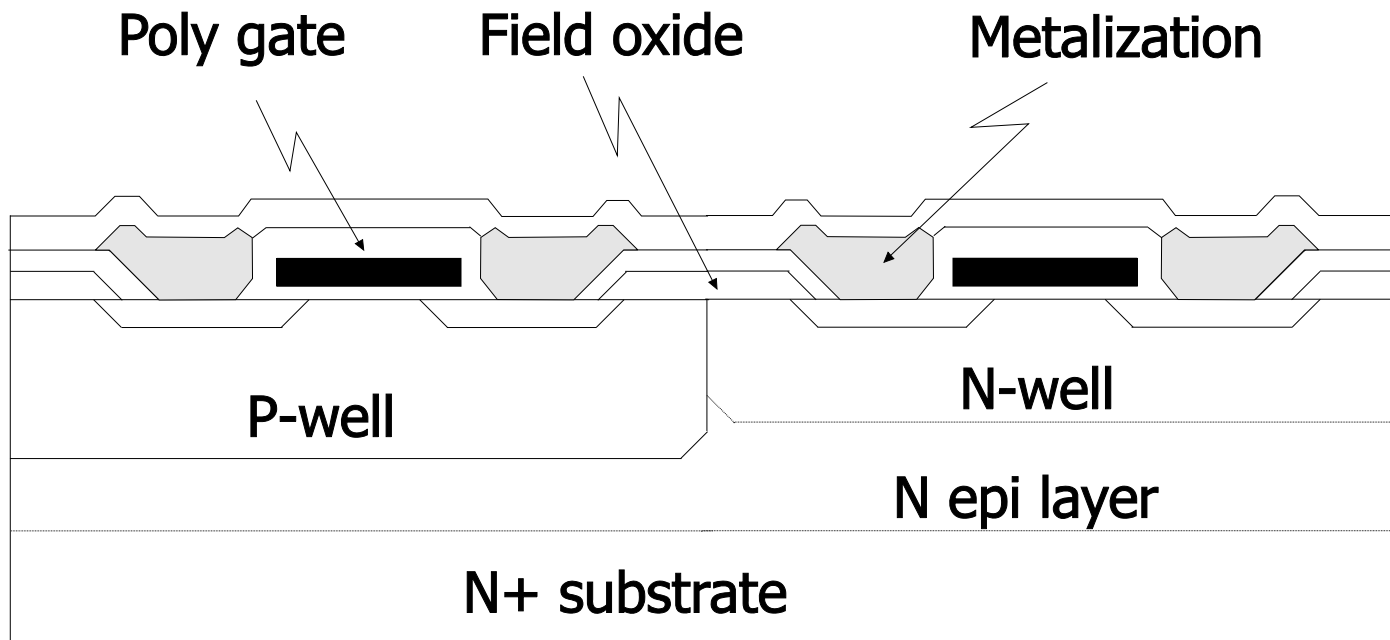
Michael A. Bridgwood - Clemson University

Report Documentation Page				Form Approved OMB No. 0704-0188	
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1. REPORT DATE JUN 2002		2. REPORT TYPE N/A		3. DATES COVERED -	
4. TITLE AND SUBTITLE Interaction with CMOS and Terminal Characteristics				5a. CONTRACT NUMBER	
				5b. GRANT NUMBER	
				5c. PROGRAM ELEMENT NUMBER	
6. AUTHOR(S)				5d. PROJECT NUMBER	
				5e. TASK NUMBER	
				5f. WORK UNIT NUMBER	
7. PERFORMING ORGANIZATION NAME(S) AND ADDRESS(ES) Clemson University				8. PERFORMING ORGANIZATION REPORT NUMBER	
9. SPONSORING/MONITORING AGENCY NAME(S) AND ADDRESS(ES)				10. SPONSOR/MONITOR'S ACRONYM(S)	
				11. SPONSOR/MONITOR'S REPORT NUMBER(S)	
12. DISTRIBUTION/AVAILABILITY STATEMENT Approved for public release, distribution unlimited					
13. SUPPLEMENTARY NOTES Presentations given at the First Annual Review Meeting on June 8, 2002 DoD MURI Award F49620-01-1-0436, The original document contains color images.					
14. ABSTRACT					
15. SUBJECT TERMS					
16. SECURITY CLASSIFICATION OF:			17. LIMITATION OF ABSTRACT UU	18. NUMBER OF PAGES 10	19a. NAME OF RESPONSIBLE PERSON
a. REPORT unclassified	b. ABSTRACT unclassified	c. THIS PAGE unclassified			

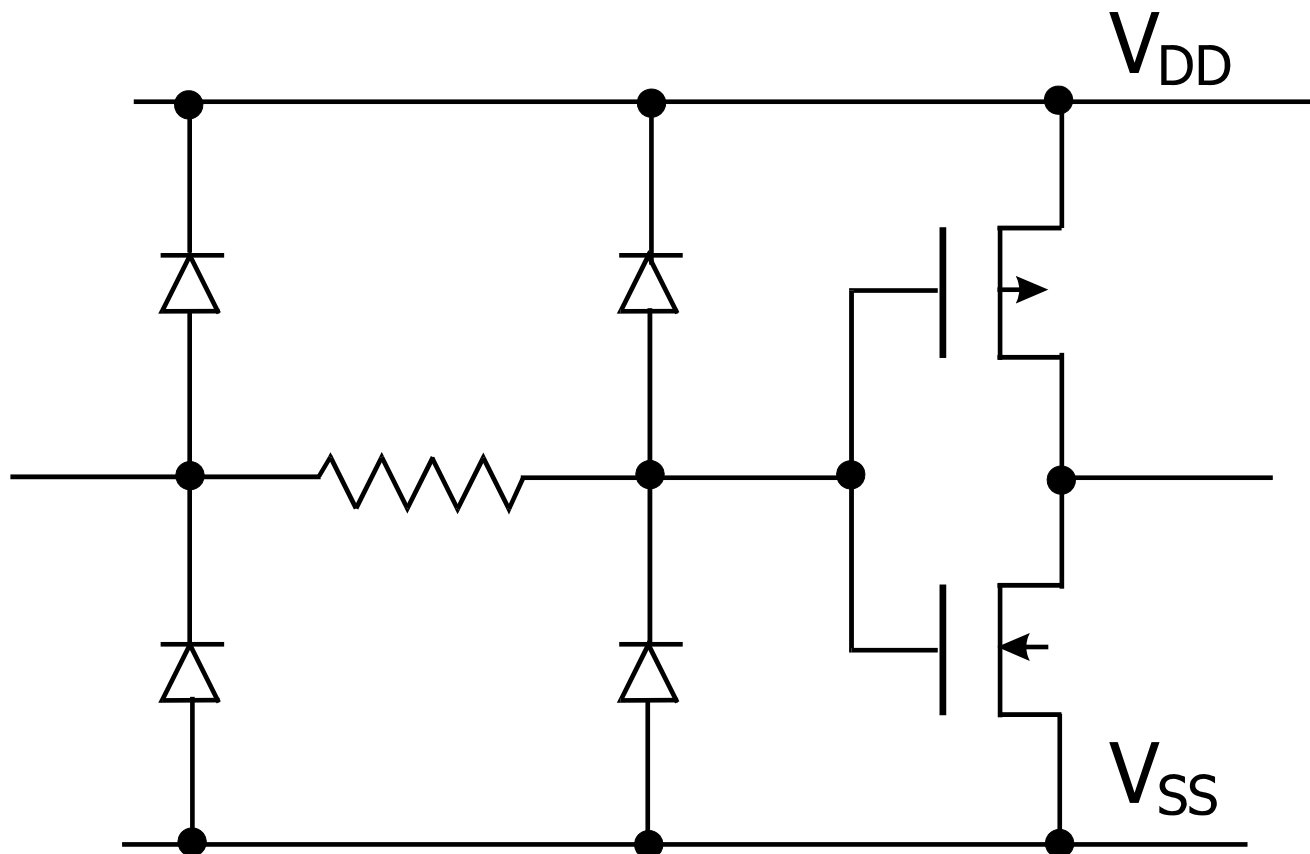
Conducted Interactions - CMOS Devices

- Mechanisms and Vulnerability Thresholds
- Impedance of Inputs through Switching
- Waveforms – Pulses and Damped Rings

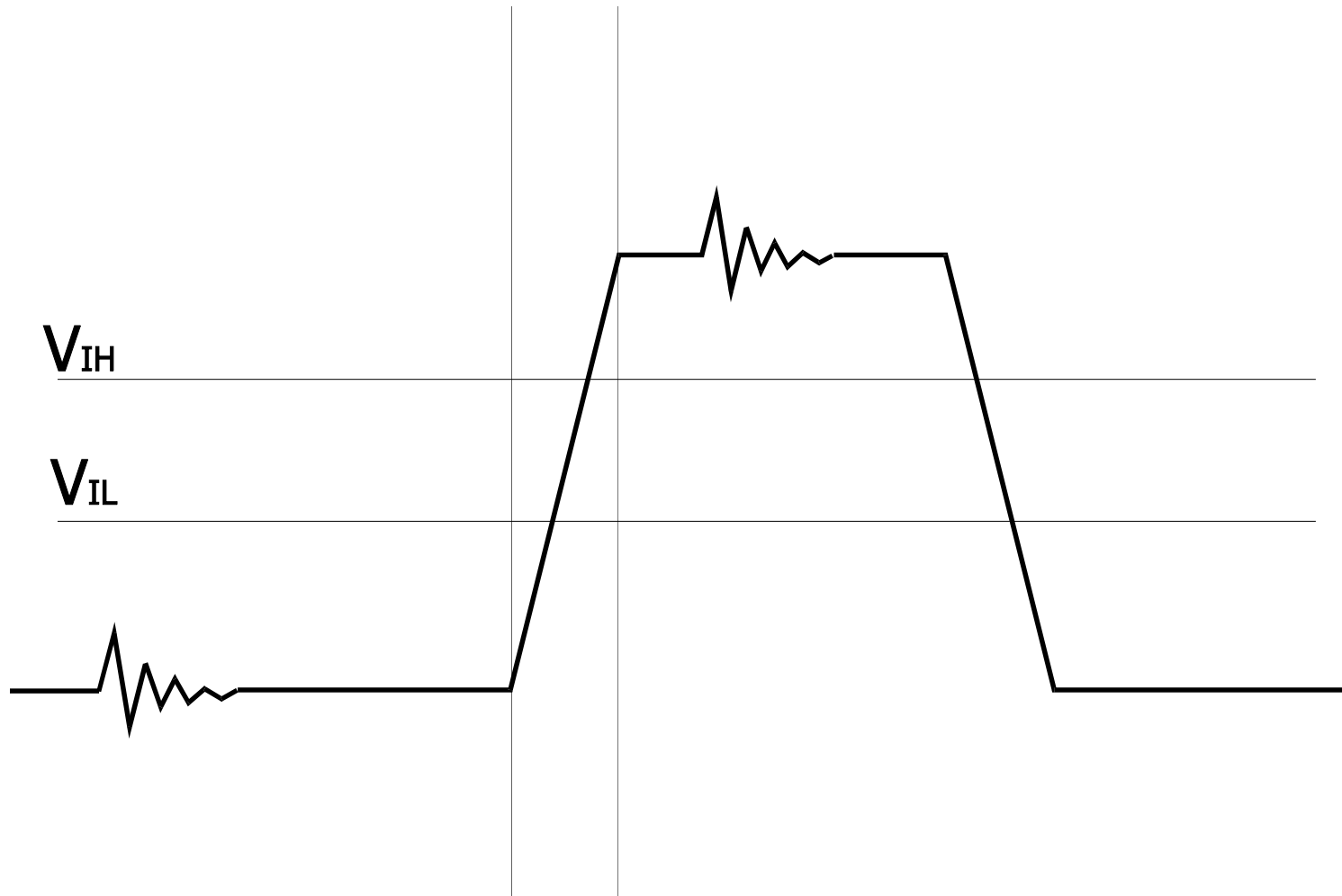
Interaction with CMOS – Mechanisms



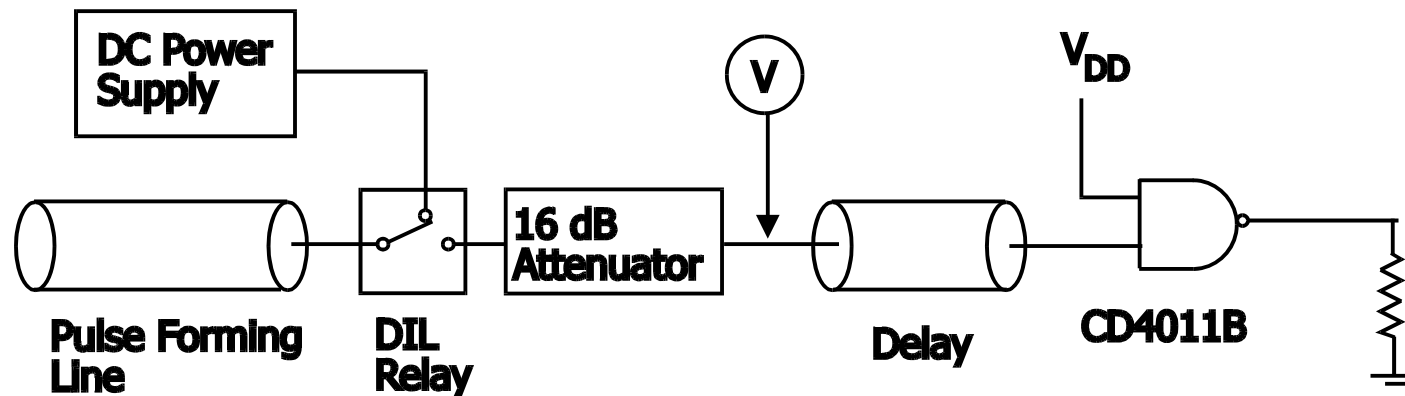
Interaction with CMOS – Input Circuit



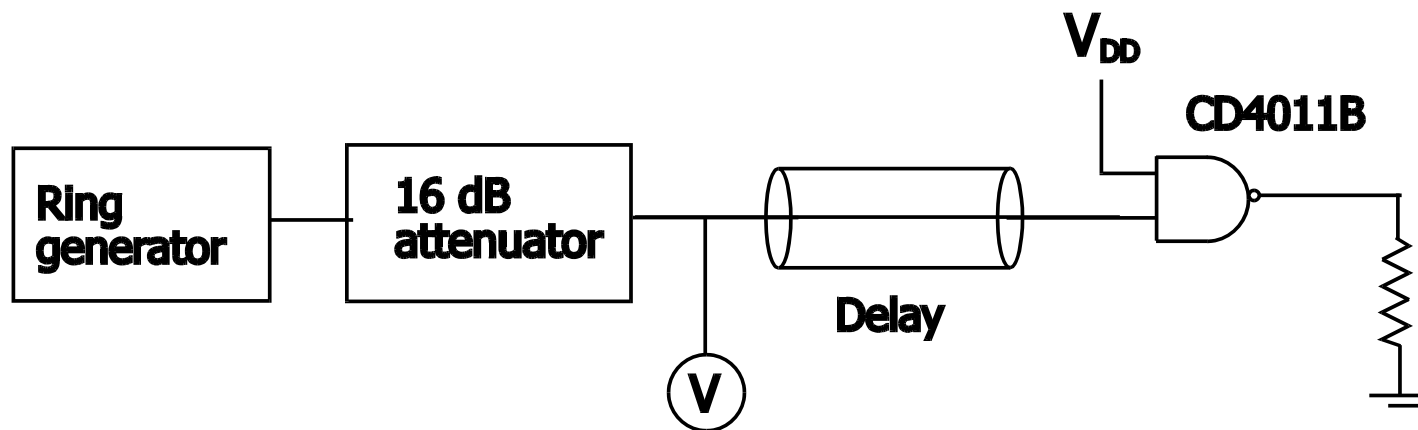
Interaction with CMOS – Ring Injection



CMOS Interactions – Injection Systems



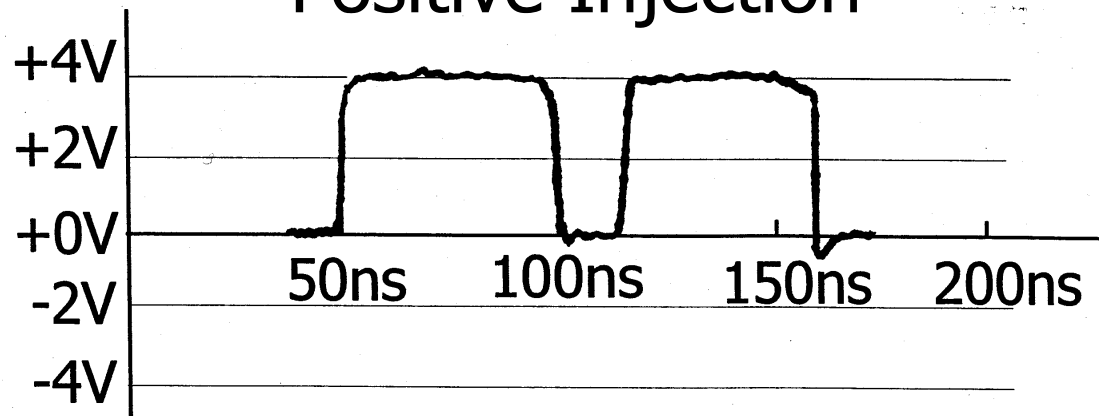
Pulse TDR System



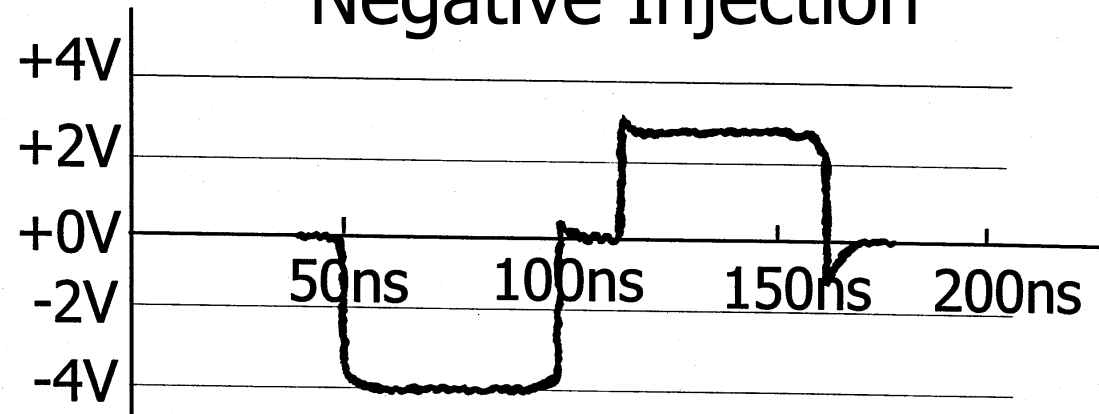
Ring TDR System

CMOS Interaction – Pulse TDR Injection

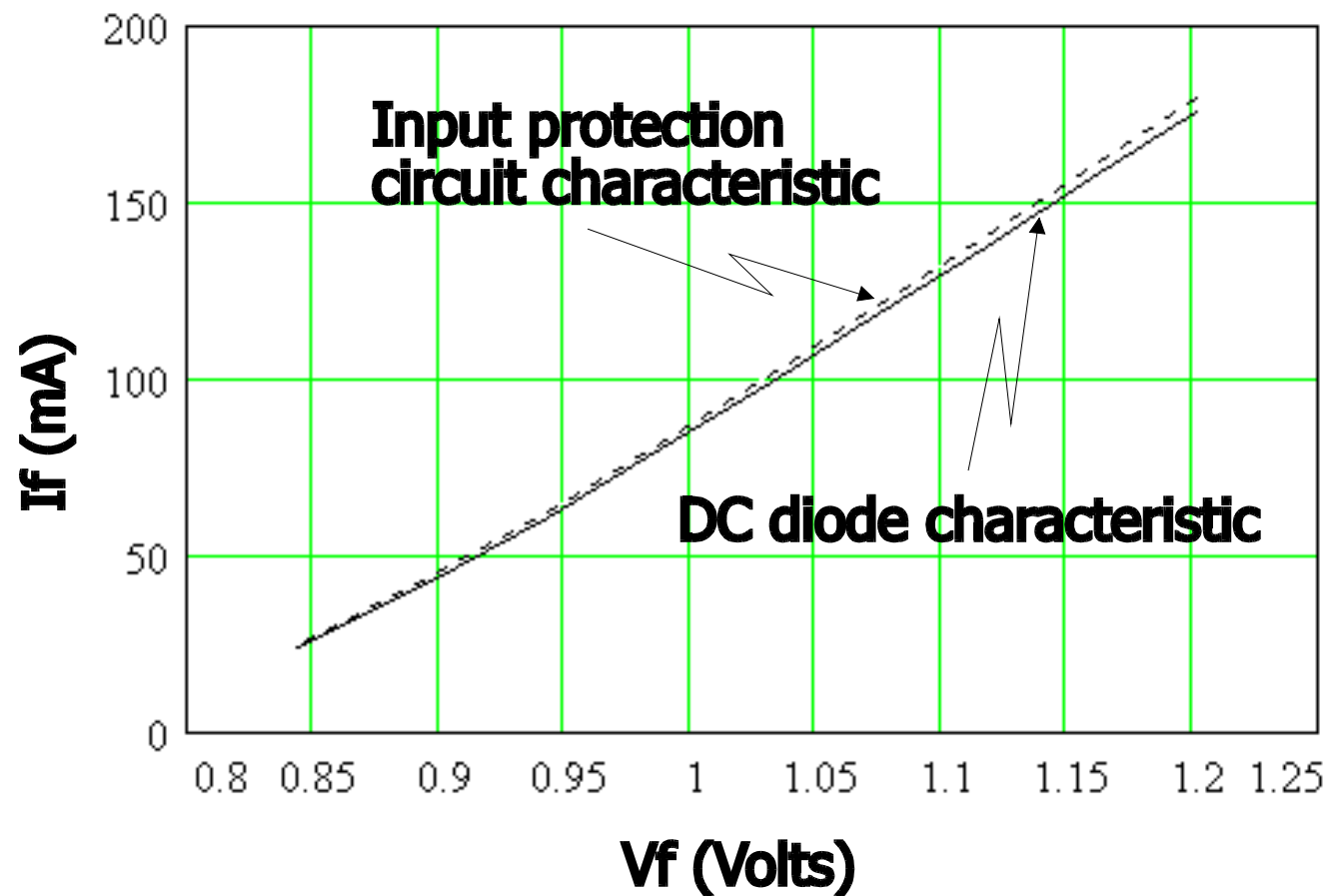
Positive Injection



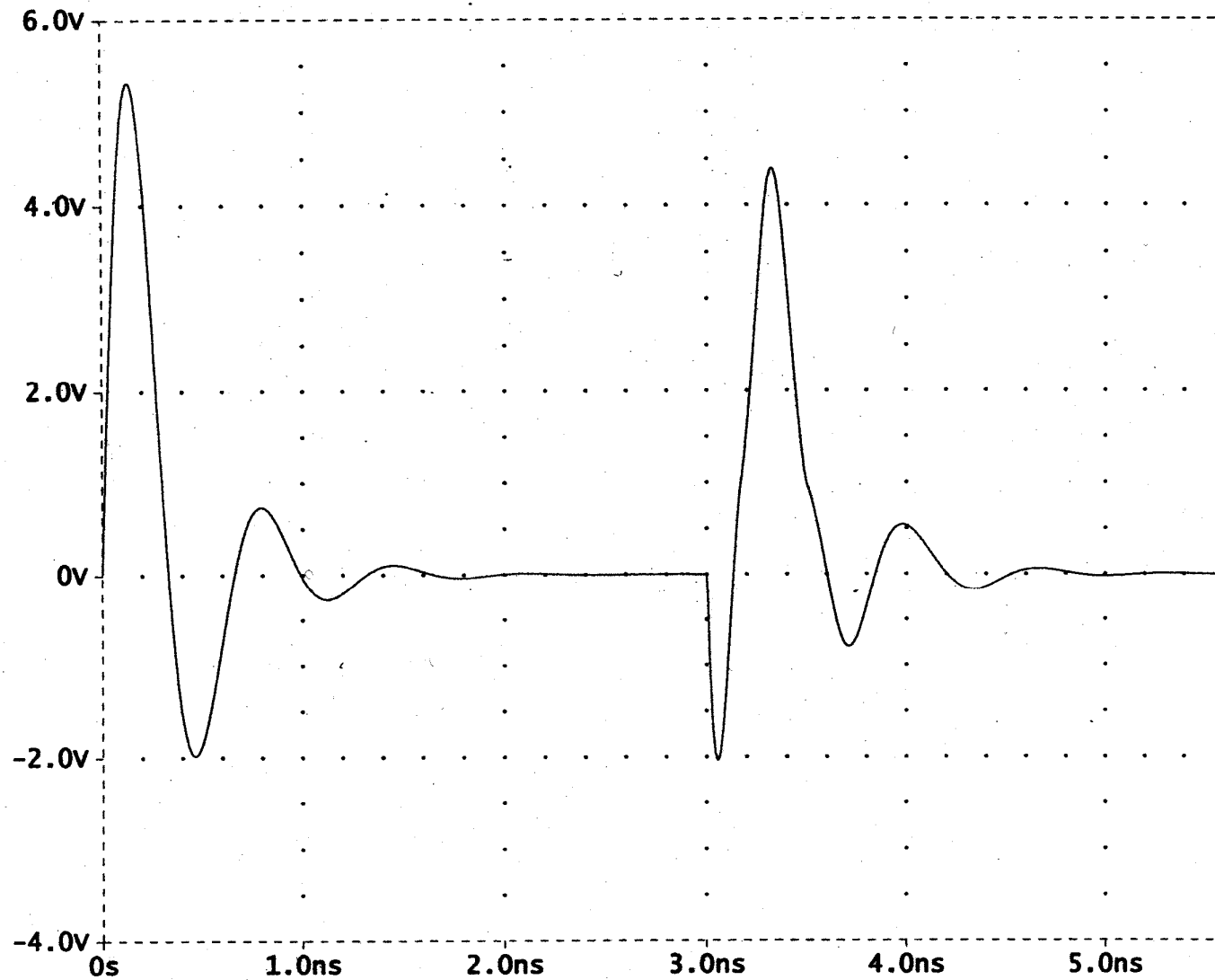
Negative Injection



CMOS Input – Pulse TDR Negative Injection



CMOS Interaction – Ringing TDR



Conducted Interactions – Future Work

- Mechanisms and Vulnerability Thresholds
- Waveforms – Pulses and Damped Rings
- Extend work to other digital devices